

Sights Unseen.

With the New JEM-2010F Field Emission Electron Microscope
You'll See It ... If It's There.

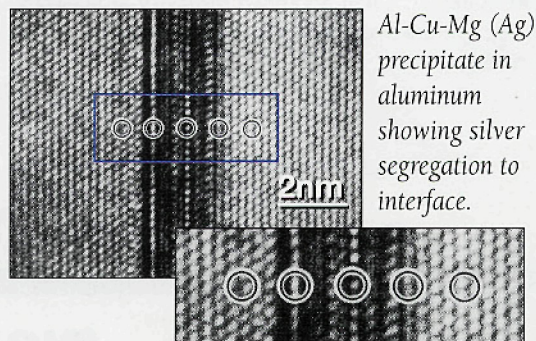
From JEOL...the newest generation of precision equipment that permits unprecedented resolution in 3-dimensional, subnanometer analysis of microstructures. Featuring user-friendly operation and long-term stability, the JEM-2010F also offers:

- Schottky Emission: High Current High Brightness
- High Probe Current: 0.5nm Probe with 100 pA Current
- High Resolution: Information Limit 1.4Å, Scherzer 1.9Å
- Holography: Option Available
- STEM Resolution: 0.2nm Magnification: 8MX

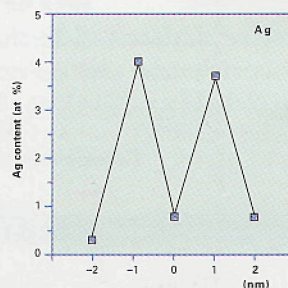
Discover the JEM-2010F and visit sights previously unseen.



JEOL USA, Inc., 11 Dearborn Road, Peabody, MA 01960
Tel: 508-535-5900 Fax: 508-536-2205 e-mail: eod@jeol.com



Al-Cu-Mg (Ag) precipitate in aluminum showing silver segregation to interface.



Data courtesy of Dr. James M. Howe, Department of Materials Science & Engineering, University of Virginia, U.S.A.